# **Power MOSFET**

# 30 V, 44 A, Single N-Channel, SO-8 FL

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Optimized for 5 V, 12 V Gate Drives
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

# **Applications**

- CPU Power Delivery
- DC-DC Converters

### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Para	Symbol	Value	Unit		
Drain-to-Source Volt	$V_{DSS}$	30	V		
Gate-to-Source Voltage			$V_{GS}$	±20	V
Continuous Drain Current R <sub>0JA</sub> (Note 1)		$T_A = 25^{\circ}C$ $T_A = 100^{\circ}C$	I <sub>D</sub>	15.5 9.8	Α
Power Dissipation R <sub>0</sub> JA (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.70	W
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	23.4	Α
Current $R_{\theta JA} \le 10 \text{ s}$ (Note 1)		T <sub>A</sub> = 100°C		14.8	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	6.13	W
Continuous Drain	State	T <sub>A</sub> = 25°C	Ι <sub>D</sub>	9.0	Α
Current R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 100°C		5.7	
Power Dissipation R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.92	W
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	44	Α
Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> =100°C		28	
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	21.6	W
Pulsed Drain Current	- A =, -b			182	Α
Current Limited by Package $T_A = 25^{\circ}C$			I <sub>Dmax</sub>	100	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C
Source Current (Body Diode)			I <sub>S</sub>	21	Α
Drain to Source DV/DT			dV/d <sub>t</sub>	6.0	V/ns
Single Pulse Drain-to-Source Avalanche Energy ( $T_J = 25$ °C, $V_{DD} = 24$ V, $V_{GS} = 10$ V, $I_L = 21$ $A_{pk}$ , $L = 0.1$ mH, $R_G = 25$ $\Omega$ )			E <sub>AS</sub>	22	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			T <sub>L</sub>	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

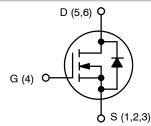
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.



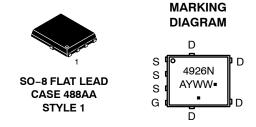
# ON Semiconductor®

#### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
30 V	7.0 mΩ @ 10 V	44 A	
30 V	12.0 mΩ @ 4.5 V	44 A	



**N-CHANNEL MOSFET** 



A = Assembly Location

Y = Year WW = Work Week

■ = Pb-Free Package (Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4926NT1G	SO-8 FL (Pb-Free)	1500 / Tape & Reel
NTMFS4926NT3G	SO-8 FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	5.8	
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	46.3	°C/W
Junction-to-Ambient - Steady State (Note 4)	$R_{\theta JA}$	136.2	C/VV
Junction-to-Ambient - (t ≤ 10 s) (Note 3)	$R_{\theta JA}$	20.4	

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
   Surface-mounted on FR4 board using the minimum recommended pad size.

# FLECTRICAL CHARACTERISTICS /T.

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•			•	•		
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				25		mV/°C
Zero Gate Voltage Drain Current	rent $I_{DSS}$ $V_{GS} = 0 \text{ V},$ $T_{J} = 25^{\circ}\text{C}$		T <sub>J</sub> = 25°C			1.0	
		V <sub>DS</sub> = 24 V	T <sub>J</sub> = 125°C			10	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>G</sub>	<sub>S</sub> = ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 250 μA	1.2	1.6	2.2	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				3.8		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 30 A		4.8	7.0	
			I <sub>D</sub> = 15 A		4.8		1
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		7.8	12	mΩ
			I <sub>D</sub> = 15 A		7.5		
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 15 A			40		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE			•	•		
Input Capacitance	C <sub>ISS</sub>				1004		
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 15 V			390		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				119		
Total Gate Charge	Q <sub>G(TOT)</sub>				8.7		
Threshold Gate Charge	Q <sub>G(TH)</sub>				1.4		1 .
Gate-to-Source Charge	Q <sub>GS</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 30 \text{ A}$			3.0		nC
Gate-to-Drain Charge	$Q_{GD}$				3.5		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 15 V; I <sub>D</sub> = 30 A			17.3		nC
SWITCHING CHARACTERISTICS (Note 6)	-			-	-		
Turn-On Delay Time	t <sub>d(ON)</sub>				8.6		
Rise Time	t <sub>r</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			36.9		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				14.7		ns
	1						

- 5. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.
  6. Switching characteristics are independent of operating junction temperatures.

5.5

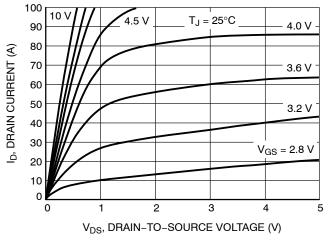
Fall Time

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 6)			•			
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V},$ $I_D = 15 \text{ A}, R_G = 3.0 \Omega$			6.6		
Rise Time	t <sub>r</sub>				31.8		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 15 \text{ A}, R_G$	= 3.0 Ω		18.3		ns
Fall Time	t <sub>f</sub>	1			4.0		1
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.87	1.1	
		$V_{GS} = 0 \text{ V},$ $I_S = 30 \text{ A}$	T <sub>J</sub> = 125°C		0.76		V
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS}$ = 0 V, dIS/dt = 100 A/ $\mu$ s, $I_{S}$ = 30 A			21.9		
Charge Time	t <sub>a</sub>				11.0		ns
Discharge Time	t <sub>b</sub>				10.9		
Reverse Recovery Charge	Q <sub>RR</sub>				8.0		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			1.00		nΗ
Drain Inductance	L <sub>D</sub>				0.005		nΗ
Gate Inductance	L <sub>G</sub>				1.84		nΗ
Gate Resistance	$R_{G}$				1.0	2.2	Ω

<sup>5.</sup> Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

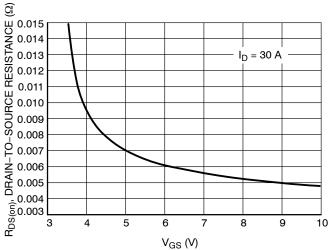
### **TYPICAL CHARACTERISTICS**



100  $T_J = -55^{\circ}C$ 90 80 ID, DRAIN CURRENT (A)  $T_J = 25^{\circ}C$ 70  $T_J = 125^{\circ}C$  $V_{DS} = 10 V$ 60 50 40 30 20 10 0 2 3 4 5 V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (V)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



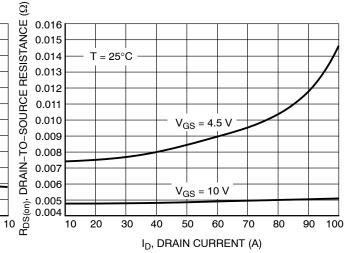
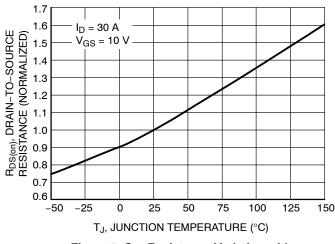


Figure 3. On-Resistance vs. V<sub>GS</sub>

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



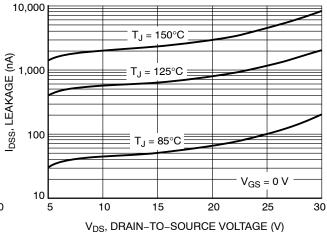


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

### **TYPICAL CHARACTERISTICS**

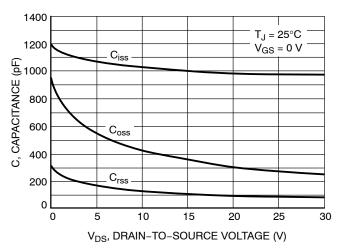


Figure 7. Capacitance Variation

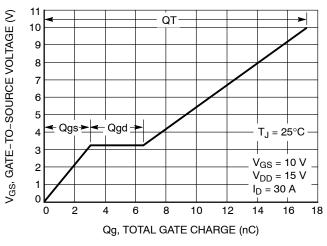


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

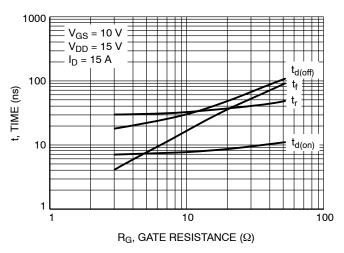


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

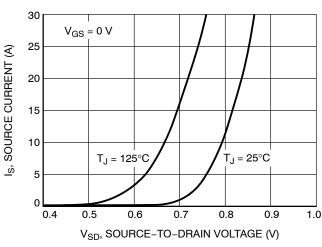


Figure 10. Diode Forward Voltage vs. Current

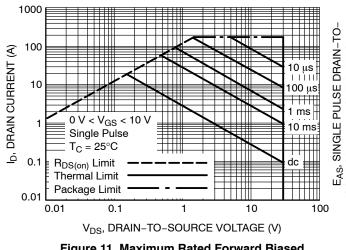
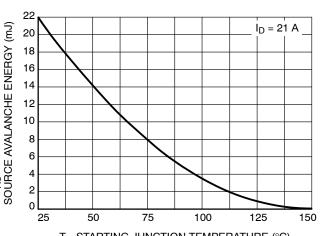


Figure 11. Maximum Rated Forward Biased Safe Operating Area



 $\mathsf{T}_\mathsf{J},\,\mathsf{STARTING}\,\mathsf{JUNCTION}\,\mathsf{TEMPERATURE}\,(^\circ\mathsf{C})$ 

Figure 12. Maximum Avalanche Energy vs.
Starting Junction Temperature

# **TYPICAL CHARACTERISTICS**

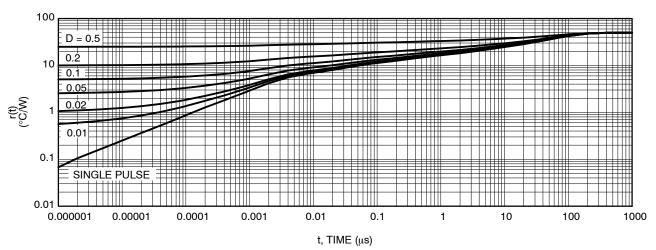
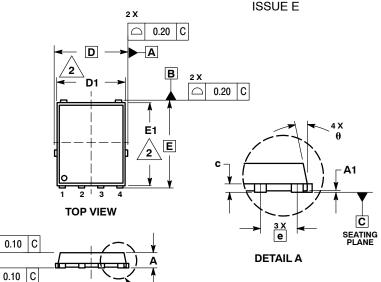


Figure 13. Thermal Response

### PACKAGE DIMENSIONS

## DFN5 5x6, 1.27P (SO8 FL) CASE 488AA-01



**DETAIL A** 

STYLE 1: PIN 1. SOURCE 2. SOURCE 3. SOURCE

4. GATE 5. DRAIN

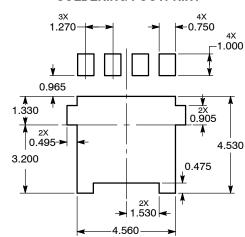
6. DRAIN

#### NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	0.90	1.00	1.10		
A1	0.00		0.05		
b	0.33	0.41	0.51		
С	0.23	0.28	0.33		
D		5.15 BSC	;		
D1	4.50	4.90	5.10		
D2	3.50		4.22		
E	6.15 BSC				
E1	5.50	5.80	6.10		
E2	3.45		4.30		
е	1.27 BSC				
G	0.51	0.61	0.71		
K	0.51				
L	0.51	0.61	0.71		
L1	0.05	0.17	0.20		
М	3.00	3.40	3.80		
θ	0 °		12 °		

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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